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Applicati n Number	09/375,627			
Filing Date	August 17, 1999			
First Named Inventor	Hans Loschner, et al.			
Group Art Unit	1756			
Examiner Name	Unknown			
Attorney Docket Number	99108			

	U.S. PATENT DOCUMENTS						
Examiner Initials	Cite No.1	U.S. Patent Docum Kind (Number (if kno	Code ²	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	
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		OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS	
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